

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10791046	DREGE ET AL.
	<b>Examiner</b> Hirl, Joseph P	<b>Art Unit</b> 2129

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
706	12, 14, 46, @ad<20040301	9/25/7	JPH
700	110, @ad <2004 03 01	9/25/7	JPH

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East: all data bases, profile, model, parameter, training, machine, diffraction, signal, optimized, termination, @ad<20040301	9/25/7	JPH
IEEE: profile, model, learning machine, diffraction, @ad<20040301	9/25/7	JPH
Inventors: Drege, Doddi, Bao		

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>